



Form PTO-1449 (modified)		Atty. Docket No. ESSR:090US	Serial No. 10/523,951
List of Patents and Publications for Applicant's  INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		Applicant Karin Scherer et al.	
		Filing Date: February 8, 2005	Group: 2874
U.S. Patent Documents <i>See Page 1</i>	Foreign Patent Documents <i>See Page 1</i>	Other Art <i>See Page 1</i>	

**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.

**Foreign Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
/JL/	B1	EP 0 975 017	1/26/00	Europe			
/JL/	B2	EP 11264903	9/28/99	Japan			Abstract
/JL/	B3	JP 05215929	8/27/93	Japan			Abstract
/JL/	B4	WO 02/11195	2/7/02	WIPO			Abstract

**Other Art (Including Author, Title, Date Pertinent Pages, Etc.)**

Exam. Init.	Ref. Des.	Citation
/JL/	C1	Lee and Hwangbo, "Inhomogeneous refractive index of SiOxy thin films prepared by ion beam assisted deposition," <i>Surface and Coatings Technology</i> , 128-129:280-285, 2000.

25536164.1

EXAMINER: /Jonathan Langman/	DATE CONSIDERED: 06/22/2007
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